SERIES S16 · TEST & DUMMY

Test and dummy grade silicon wafers



Cost-effective wafers for deposition runs, process calibration, spin-coating trials, metrology set-up and tool qualification. Same diameters as prime wafers with relaxed thickness, resistivity and surface specifications.

- Test grade: specified type, polished front
- Dummy grade: any type / resistivity, for handling and set-up
- Ideal for ellipsometry, profilometry and film-stress tests
- Packs of 25 wafers

CONFIGURATIONS

Ref. No.	Diameter	Grade	Thickness	Type / resistivity	Surface	Price
S1601	2"	Test	SEMI ± 25 µm	P-type, 1 – 100 Ω·cm	SSP	On request
S1602	2"	Test	SEMI ± 25 µm	N-type, 1 – 100 Ω·cm	SSP	On request
S1603	3"	Test	SEMI ± 25 µm	P-type, 1 – 100 Ω·cm	SSP	On request
S1604	3"	Test	SEMI ± 25 µm	N-type, 1 – 100 Ω·cm	SSP	On request
S1605	4"	Test	SEMI ± 25 µm	P-type, 1 – 100 Ω·cm	SSP	On request
S1606	4"	Test	SEMI ± 25 µm	N-type, 1 – 100 Ω·cm	SSP	On request
S1607	6"	Test	SEMI ± 25 µm	P-type, 1 – 100 Ω·cm	SSP	On request
S1608	6"	Test	SEMI ± 25 µm	N-type, 1 – 100 Ω·cm	SSP	On request
S1609	8"	Test	SEMI ± 25 µm	P-type, 1 – 100 Ω·cm	SSP	On request
S1610	8"	Test	SEMI ± 25 µm	N-type, 1 – 100 Ω·cm	SSP	On request
S1611	2"	Dummy	Not guaranteed	Any	SSP or etched	On request
S1612	3"	Dummy	Not guaranteed	Any	SSP or etched	On request
S1613	4"	Dummy	Not guaranteed	Any	SSP or etched	On request
S1614	6"	Dummy	Not guaranteed	Any	SSP or etched	On request
S1615	8"	Dummy	Not guaranteed	Any	SSP or etched	On request

Specifications are typical values; every lot ships with a Certificate of Conformance, and measured data are available on request. Prices on request.